

## **ZVxPlus**

**- Characterisation of  
Nonlinear RF/HF Components  
in Time and Frequency domain -**



An extension kit for Rohde and Schwarz ZVA and ZVT

# Outline

- Motivation
- VNA Evolution
- LSNA Measurements and Calibration
- ZVxPlus
  - What?
  - Capabilities
  - Theory of Operation
  - Customisation
  - From small- to large-signal measurements in one connection
- Conclusion

# The Market Trend

- RF and HF Components and Circuits = “More for Less”
  - Higher efficiency (power & bandwidth)
  - More complex (circuits & modulation schemes)
  - Smaller, cheaper, shorter time to market
- Nonlinear behaviour of components can no longer be ignored
- Interaction between instruments and devices may lead to wrong conclusions
- Existing characterisation techniques are no longer sufficient

Growing need to characterise  
the nonlinear behaviour of components  
in time and frequency domain  
at DUT reference plane

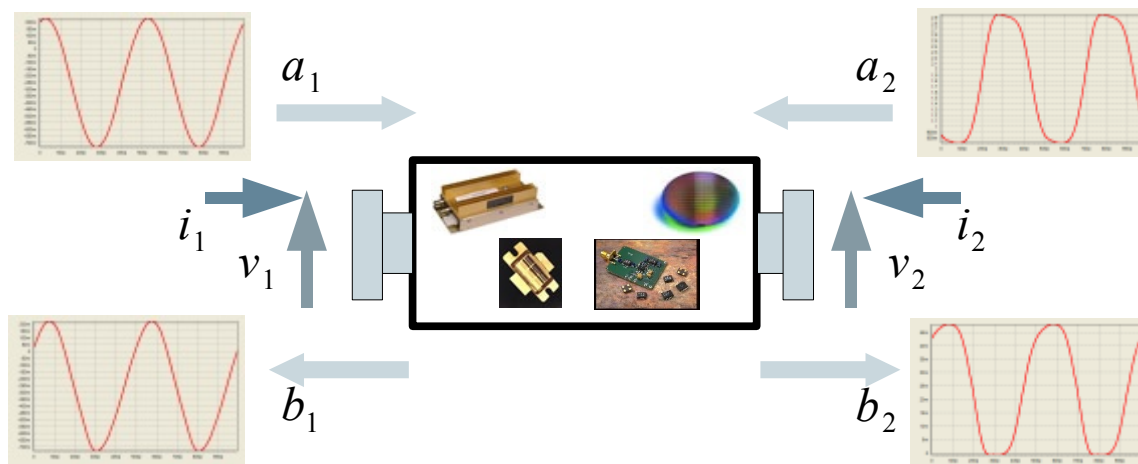
# Existing Characterisation Techniques

- Existing approaches
  - Power Measurements
  - Spectrum Analysis – Compression - TOI
  - Vector Signal Analysis - EVM
  - AM-AM and AM-PM
  - Source- and Load-pull
- The problem
  - “Limited visibility”
    - Lacking the basic information to gain insight
    - Difficult to perform a step by step diagnostics
  - Instrument – component interaction
    - Impact on (assumed) excitations
    - Impact on results and specifications
  - Different setups
    - Different skill sets
    - Different calibration techniques



# The New Characterisation Technique

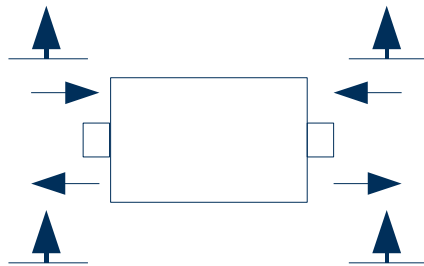
- “**Large-Signal Network Analysis**” is
  - Measuring the “complete” behaviour of a device under test i.e. the **v and i (or a and b) at all DUT ports** at the same moment
  - Accurately
  - Under almost realistic conditions
    - Excitation and mismatch
  - Using a single connection
    - Including small-signal analysis



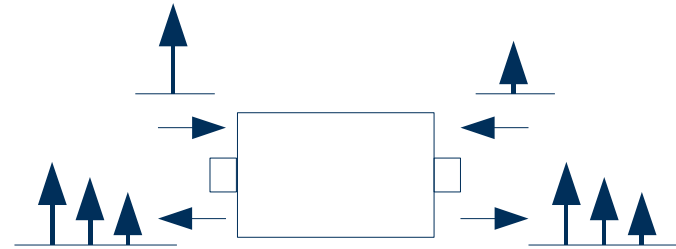
# Key Benefits

- Deal with the “**More for Less**” market trend
  - for diodes, transistors, amplifiers, multipliers, dividers, ...
- Better – More complete
  - better characterisation = improved and “LSNA-certified” models and design kits
  - better large-signal models = better design
  - better design = reduction of the number of design cycles
  - testing under realistic conditions: excitations & mismatch conditions
- Faster
  - single connection for small- and large-signal characterisation
  - measuring basic information, i.e. PAE, Pin, Pout, ... are simple derived quantities
- At reduced cost
  - applicable from device to system level
  - from R&D to T&M

# The VNA Evolution



Linear



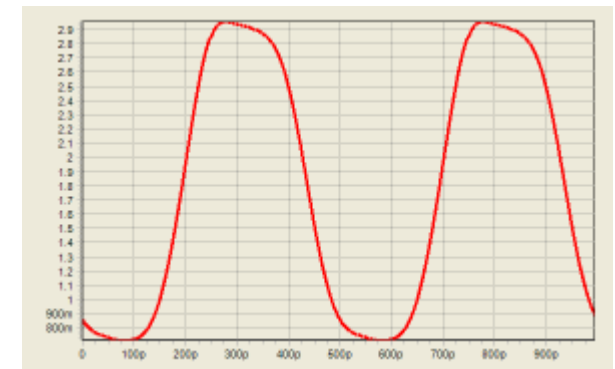
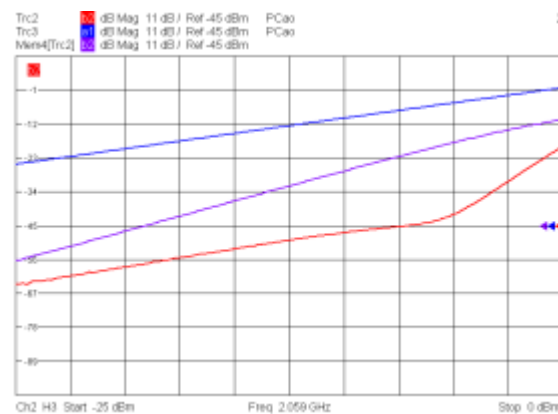
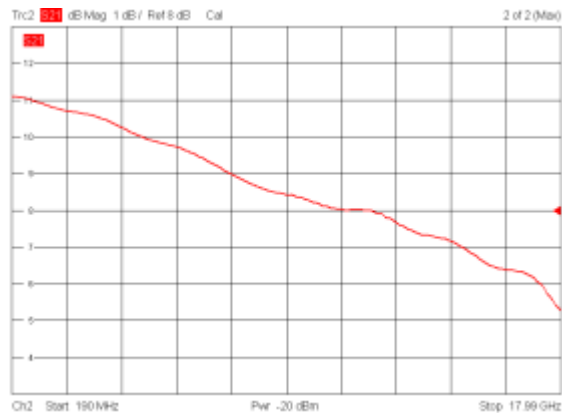
Nonlinear

S-parameters

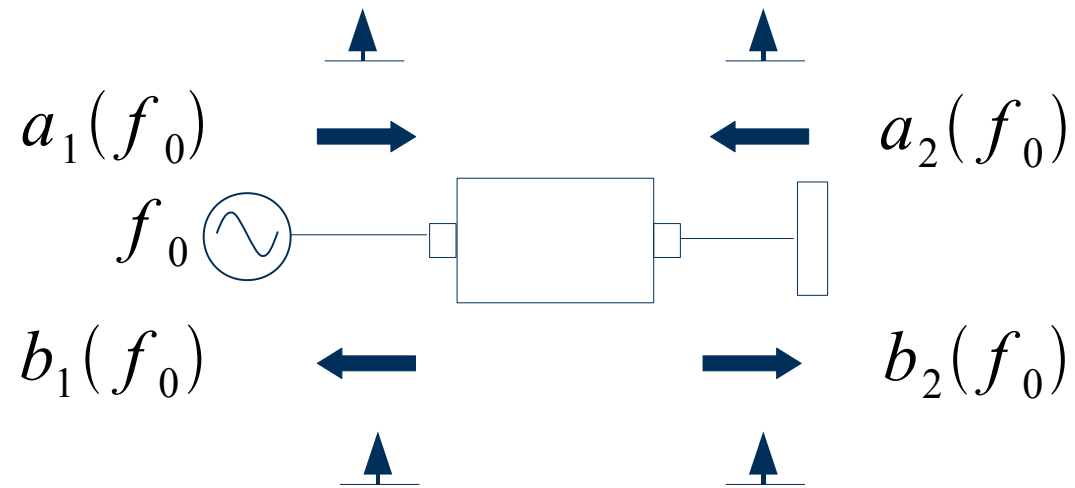
Power of  
Harmonics  
and Intermodulation

ZVxPlus

Phase  
of Harmonics



# One VNA Measurement



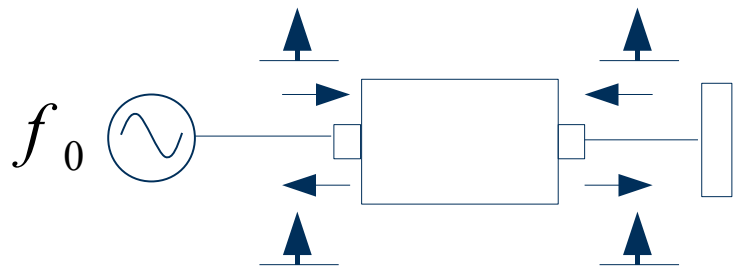
**Measuring:**

$$\frac{b_1(f_0)}{a_1(f_0)}, \frac{b_2(f_0)}{a_1(f_0)}, \frac{a_2(f_0)}{a_1(f_0)}$$

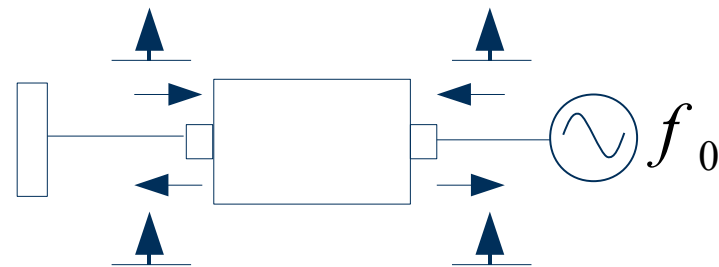
**Basic quantities  $\neq$  S-parameters**



# S-parameters



Forward Measurement



Reverse Measurement



$$\begin{aligned} b_1 &= S_{11} a_1 + S_{12} a_2 \\ b_2 &= S_{21} a_1 + S_{22} a_2 \end{aligned}$$

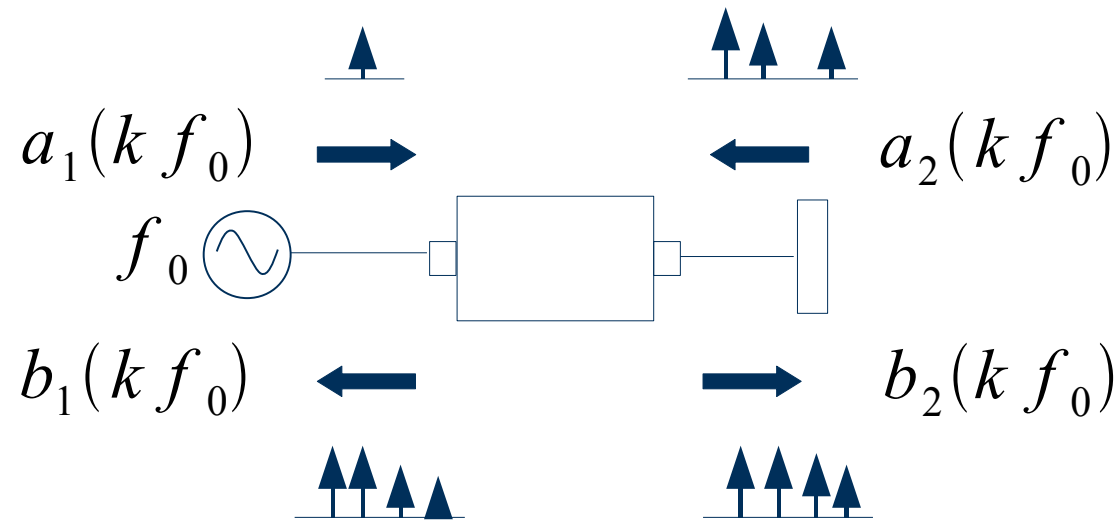


S-parameters

Mathematics  
[Linear Model]  
[**SUPERPOSITION**]

Behavioural Model

# One LSNA Measurement



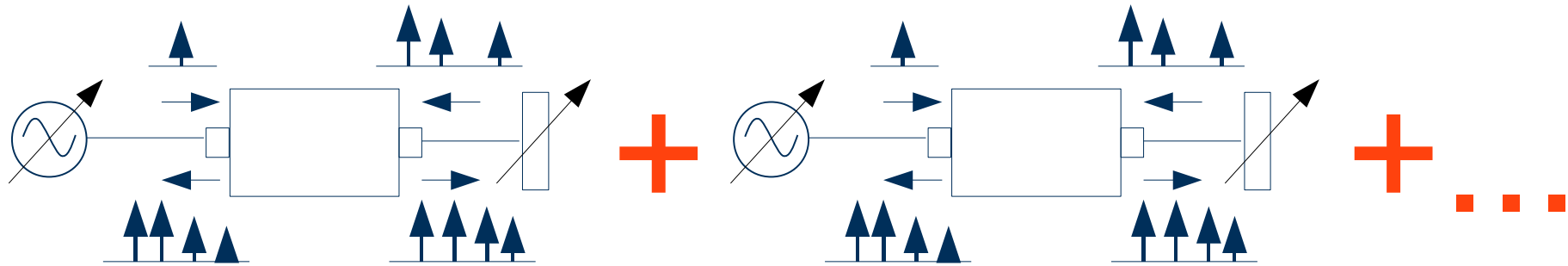
$$a_1(k f_0), b_1(k f_0), a_2(k f_0), b_2(k f_0)$$

**Measuring:**

**OR**

$$v_1(k f_0), i_1(k f_0), v_2(k f_0), i_2(k f_0)$$

# ???-parameters



Forward Measurement

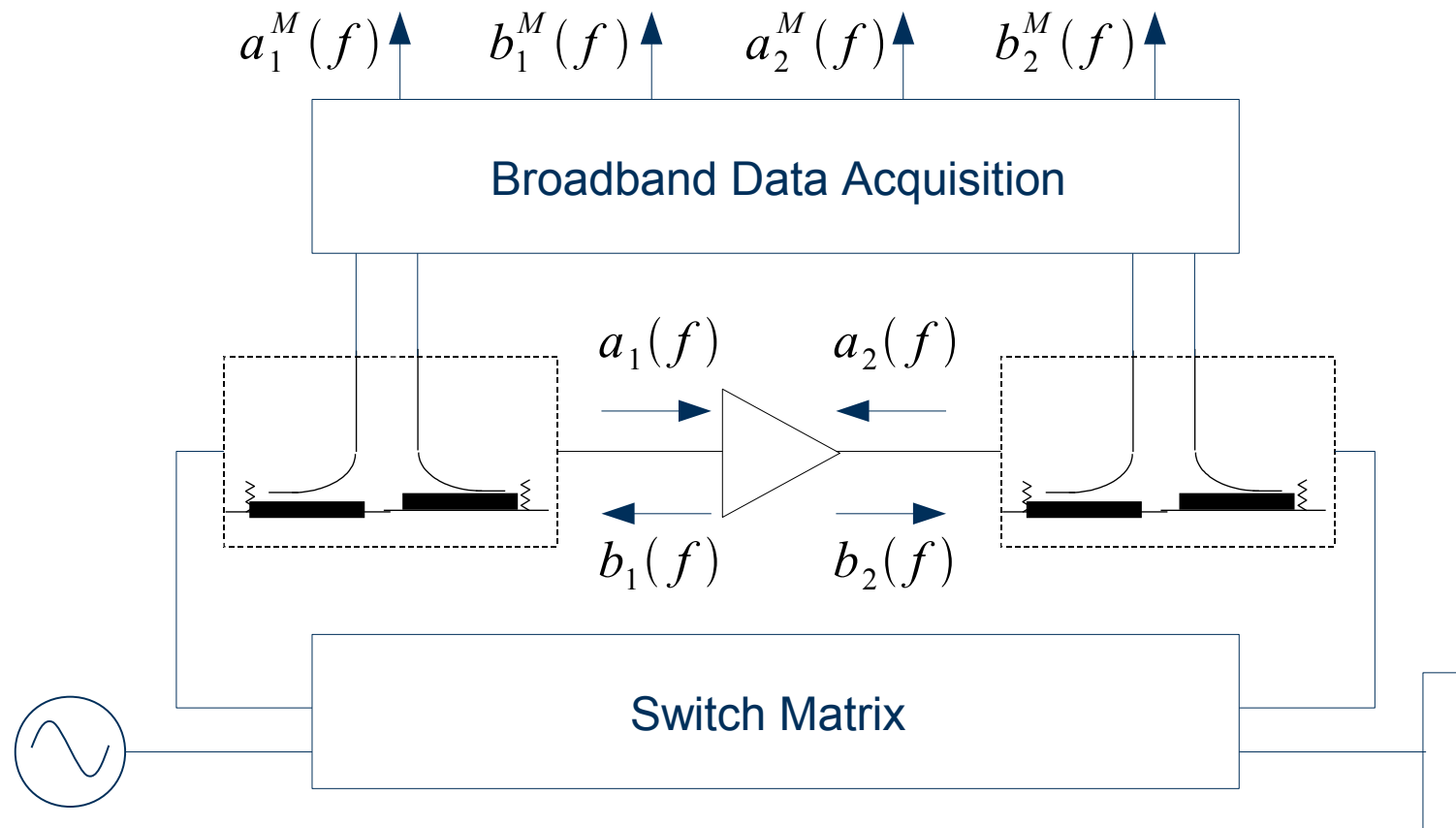
Another Forward Measurement

$$+ \begin{matrix} b_1 = F(a_1, a_2) \\ b_2 = G(a_1, a_2) \end{matrix} = \text{???-parameters}$$

Mathematics  
[Many possible Nonlinear Models]  
[**NO SUPERPOSITION**]

Behavioural Model  
[**VALIDITY - BOUNDARIES**]

# Block diagram of a Large-Signal Network Analyser



$$\begin{bmatrix} a_1 \\ b_1 \\ a_2 \\ b_2 \end{bmatrix} (f) = K(f) \begin{bmatrix} 1 & M_{12} & M_{13} & M_{14} \\ M_{21} & M_{22} & M_{23} & M_{24} \\ M_{31} & M_{32} & M_{33} & M_{34} \\ M_{41} & M_{42} & M_{43} & M_{44} \end{bmatrix} (f) \begin{bmatrix} a_1^M \\ b_1^M \\ a_2^M \\ b_2^M \end{bmatrix} (f)$$

# Calibration Techniques

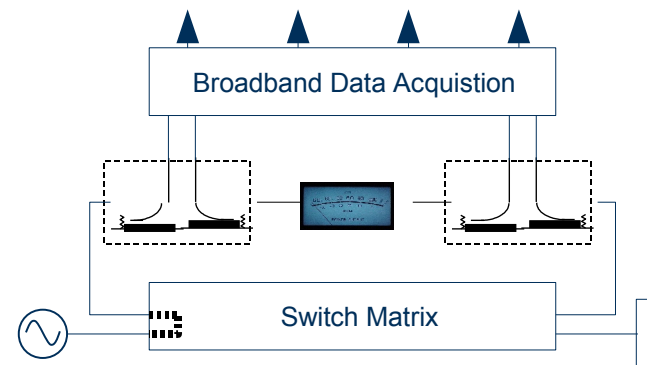
- Step 1: Relative Calibration Technique

- Same as the regular VNA calibration
- Traceable to standards

$$M_{ij} \begin{bmatrix} a_1 \\ b_1 \\ a_2 \\ b_2 \end{bmatrix}(f) = K(f) \begin{bmatrix} 1 & M_{12} & M_{13} & M_{14} \\ M_{21} & M_{22} & M_{23} & M_{24} \\ M_{31} & M_{32} & M_{33} & M_{34} \\ M_{41} & M_{42} & M_{43} & M_{44} \end{bmatrix}(f) \begin{bmatrix} a_1^M \\ b_1^M \\ a_2^M \\ b_2^M \end{bmatrix}(f)$$

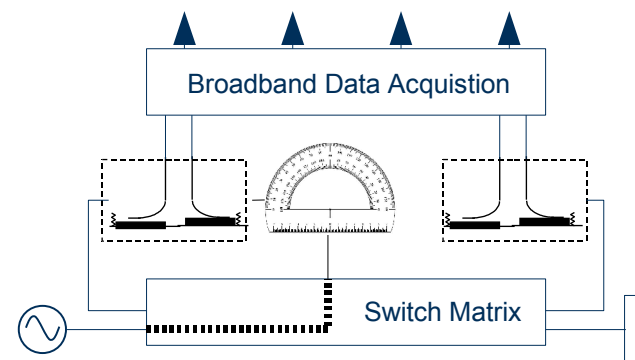
- Step 2: Power calibration  $|K|$

- Power meter and sensor
- Characterization of power distortion
- Traceable to standards

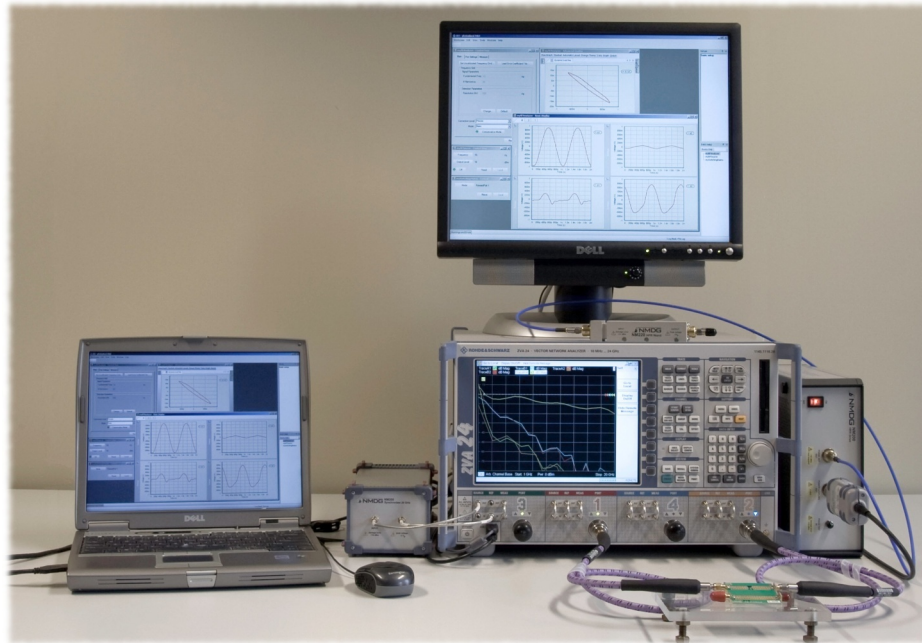


- Step 3: Phase calibration  $\Phi(K)$

- Phase reference generator
- Characterization of phase distortion
- Traceable to NIST standard



- Remark: On-wafer and fixture calibration require additional steps



## ZVxPlus

=

### 4-port ZVA or ZVT

- direct gen. & rec. access (B16)
- frequency conversion (K4)
- meas. rec. step att. (opt.) (B3x)

+

### Hardware

- synchroniser
- harmonic phase ref.

+

### Software

- configuration
- absolute calibration
- measurements

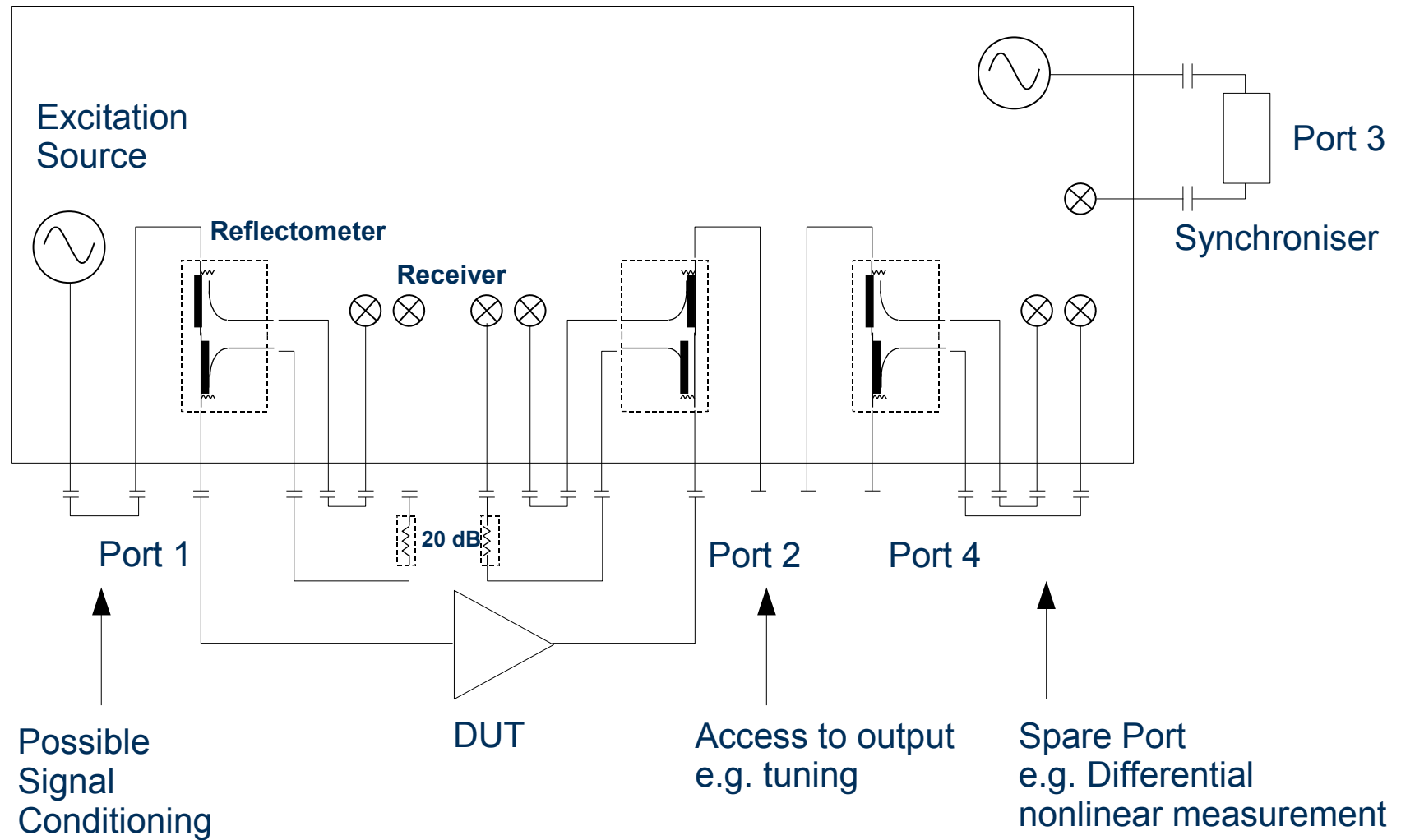
# Key Capabilities

**Aimed at the characterisation of the nonlinear harmonic behaviour  
of active components and circuits  
(e.g. diodes, transistors, amplifiers, multipliers, dividers)**

**by providing**

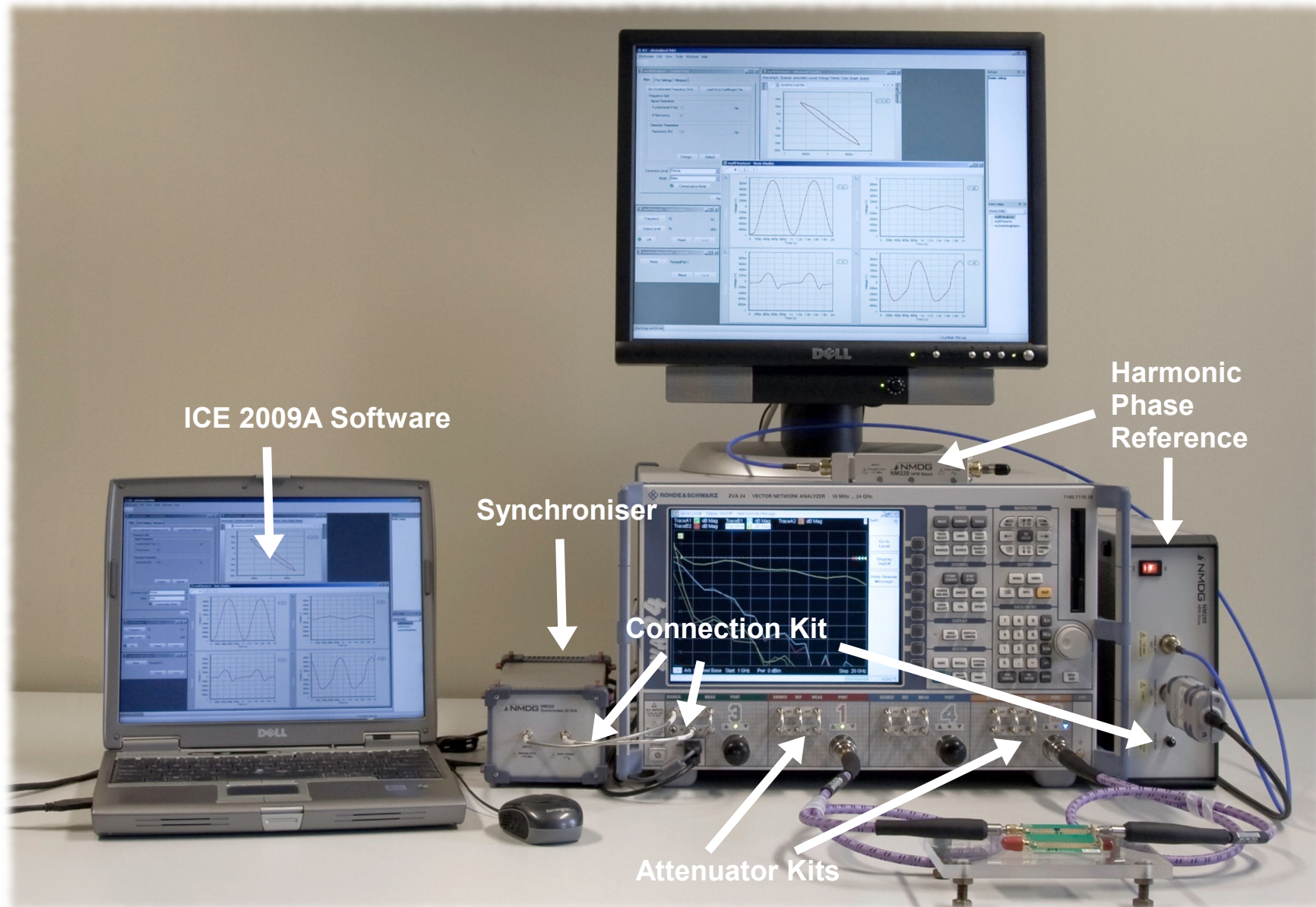
- Amplitude and phase of fundamental and harmonics
- Incident and reflected waves or voltages and currents
- In frequency and time domain
- Under mismatched conditions (non-50 Ohm)
- Connectorised and on-wafer measurement and calibration
- Overrange detection and autoranging capability
- 3D Dynamic loadline, mapping DC and HF conditions
- Derived quantities: Pin, Pout, Gain, PAE, input & output impedances
- Integration with Source – and Load-pull: fundamental and harmonic tuning
- Customisation for power applications
- Customisation to solve a customer problem

# Block diagram of standard ZVxPlus





# ZVxPlus Parts



# ZVxPlus Details

## **NM300 600MHz-20GHz Kit** includes:

- 1x NM400 Synchronizer 600MHz-20GHz, enabling the reconstruction of time waveforms
- 1x NM200 Harmonic Phase Reference Drive Box + 1x NM210 Harmonic Phase Reference Wand 600MHz-20GHz, supporting the required phase calibration
- 1x NM301 3.5mm Connection Kit, including cables and adapters
- 1x ICE 2009A Software License
- One year warranty and support

# ZVxPlus Options

## Adapter Kits

- **NM300-10** 2.4mm to 3.5mm adapter option for NM301, required for R&S®ZVA50

Attenuator Kits, required **per port** when corresponding internal step attenuator is missing (option B31 and/or B32)

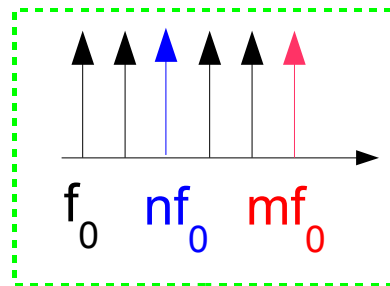
- **NM300-20** 20GHz attenuator option for R&S®ZVT20 / R&S®ZVA24
- **NM300-40A** 20GHz attenuator option for R&S®ZVA40  
or  
**NM300-40B** 40GHz attenuator option for R&S®ZVA40
- **NM300-50A** 20GHz attenuator option for R&S®ZVA50  
or  
**NM300-50B** 50GHz attenuator option for R&S®ZVA50

# VNA as LSNA: Theory of Operation

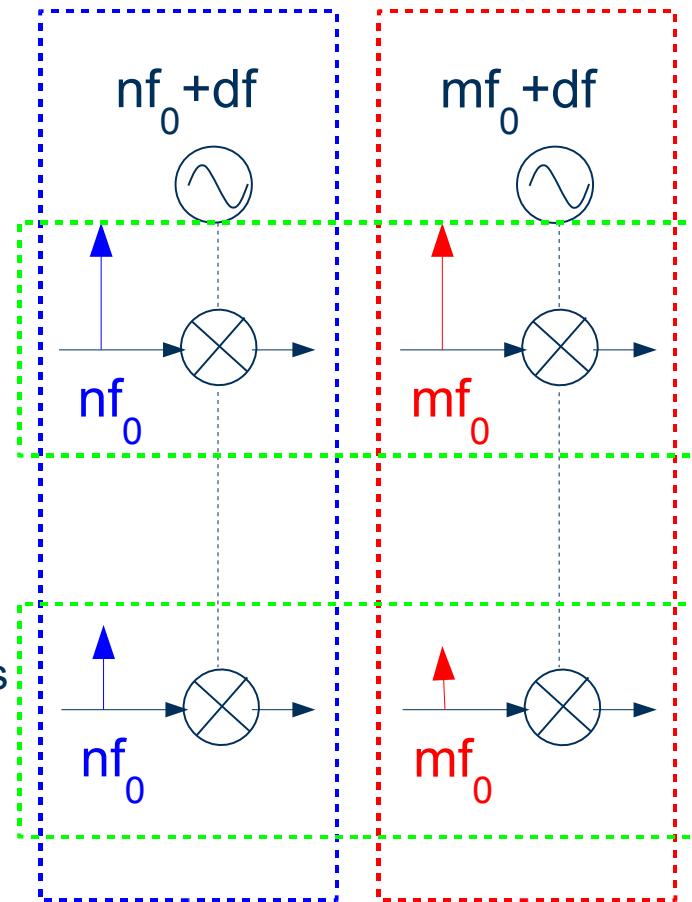
## mixer-based VNA

guarantees  
phase consistency  
between receivers

measures  
**one frequency**  
at the time



“reference”  
receiver  
a3



Phase consistency

Synchroniser

DUT

**Synchroniser**

adds phase consistency  
between fundamental and harmonics

# References

- U. LOTT, "Measurement of Magnitude and Phase of Harmonics Generated in Nonlinear Microwave Two-Ports", *IEEE Transaction on Microwave Theory and Techniques*, vol. 37, n°10, October **1989**, pp. 1506-1511
- D. BARATAUD, et al., "Measurements of time domain voltage/current waveforms at R.F. And microwave frequencies, based on the use of a Vector Network Analyzer, for the characterization of nonlinear devices. Application to high efficiency power amplifiers and frequency multipliers optimization", *IEEE Transactions on Instrumentation and Measurement*, vol. 47, n°5, October **1998**, pp.1259-1264

# NM300 ZVxPlus: Specifications

based on a 4-port R&S®ZVA24	Value	Remarks:
<b>Frequency range</b>	<b>600 MHz – 20 GHz</b>	<b>limited by phase calibration</b>
<b>Minimal frequency grid spacing</b>	<b>600 MHz</b>	
<b>Power level *</b>	<b>+10 dBm</b>	<b>@ Test port</b>
<b>Absolute phase uncertainty **</b>		<b>1 σ @ 20 GHz</b>
<b>using second internal source</b>	<b>0.6°</b>	<b>independent of IF BW, due to phase variations between the internal sources</b>
<b>using external source (locked to 10 MHz)</b>	<b>6°</b>	<b>@ 100 Hz IF BW, highly dependent on external source</b>

\* *Power extension possible using optional step attenuators or external attenuators achieving maximum allowable power of +27 dBm with standard test set*

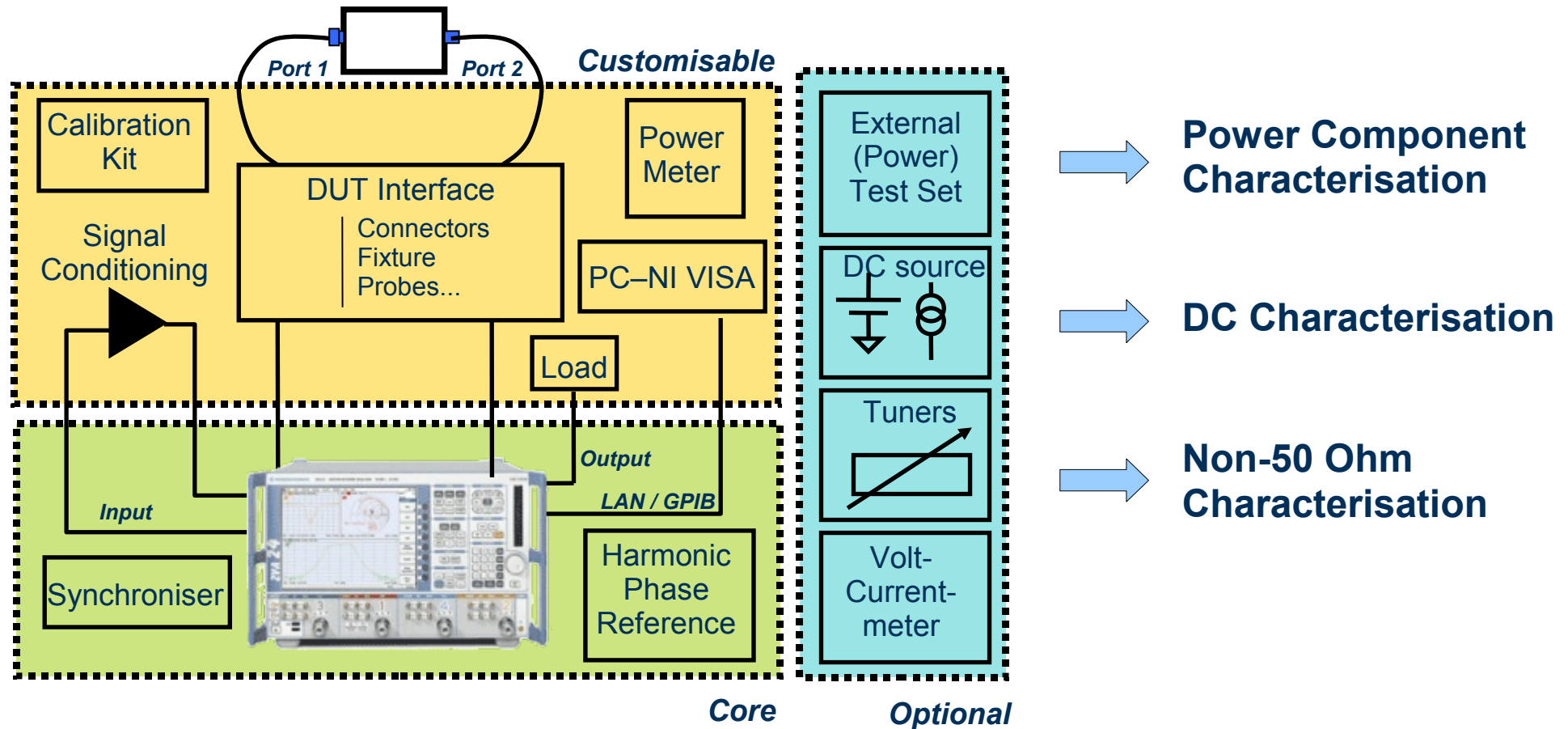
\*\* *Using one R&S®ZVA internal source to drive Synchroniser @ 600MHz*

Notes: *when additive noise is dominant, the phase standard deviation can be linked to the dBm standard deviation using the following:*

$$\sigma_{Phase(x)_{deg}} = \frac{180}{\pi} \frac{\ln(10)}{20} \sigma_{dBm(x)} \approx 6.6 \sigma_{dBm(x)}$$



# Customisation and Options

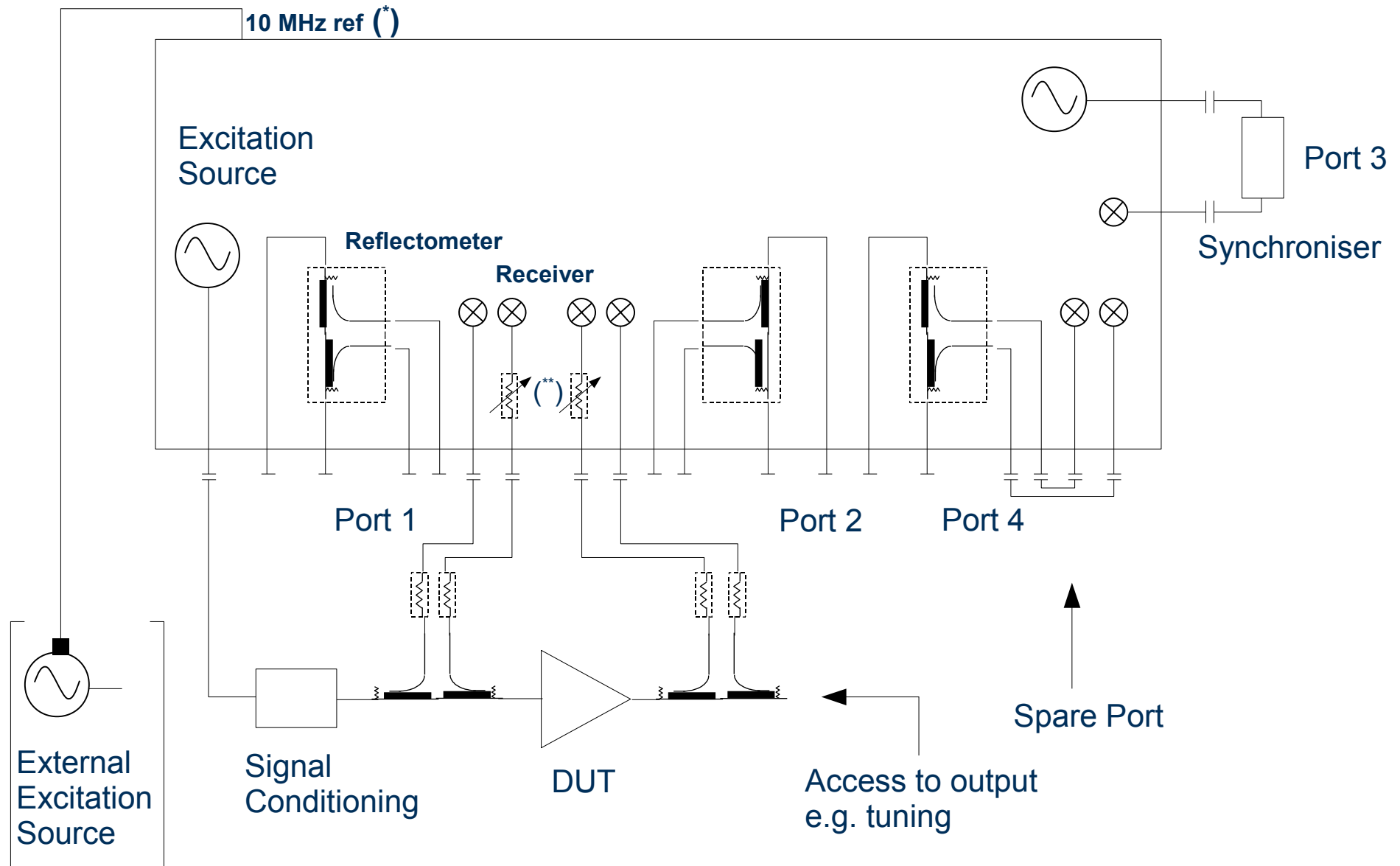


**Core:** ZVx and ZVxPlus

**Customisable:** required and supplied by customer or at additional cost

**Optional:** depending on characterisation needs, supplied by customer or at additional cost

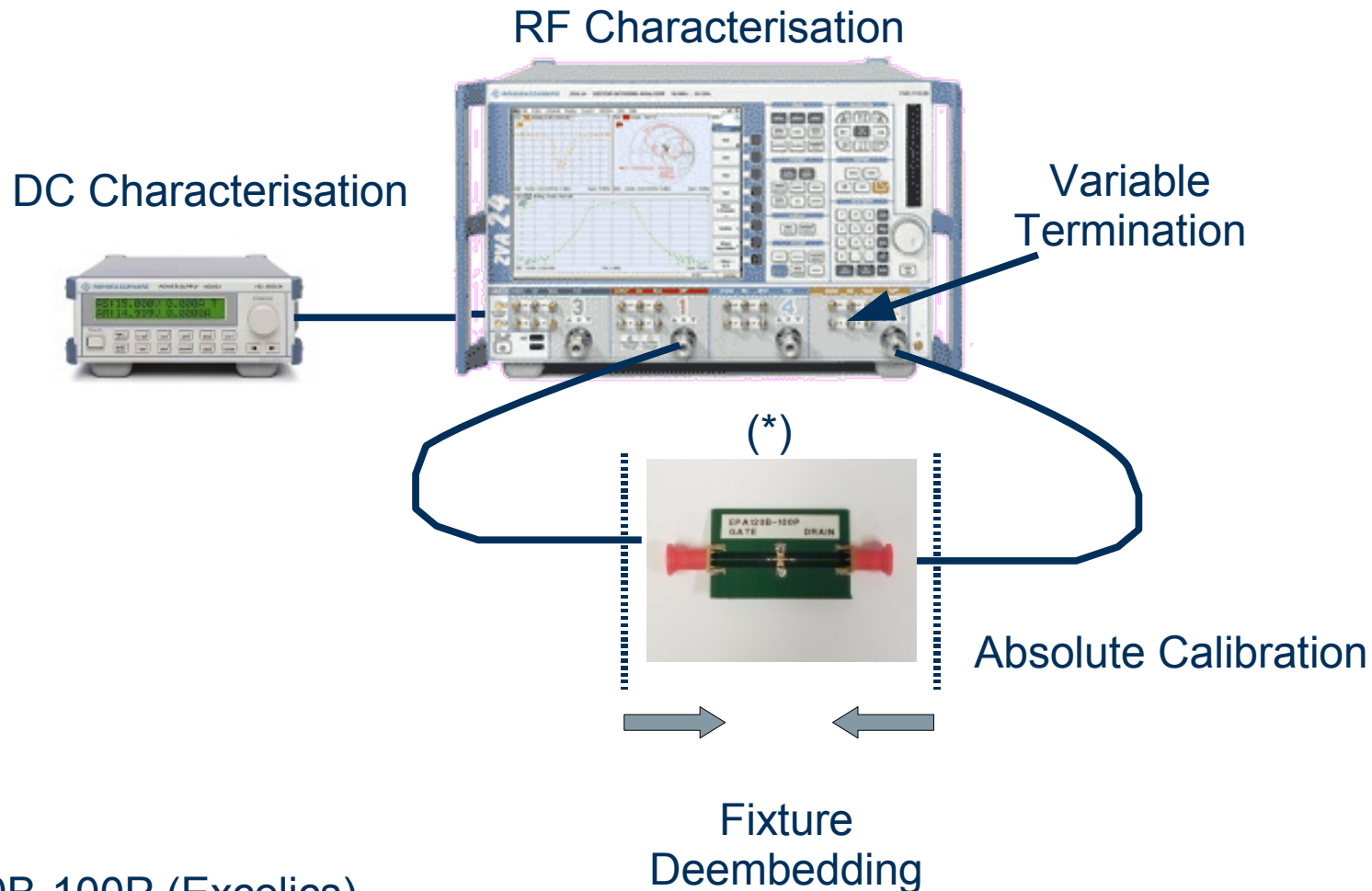
# Blockdiagram of customised ZVxPlus for Power Applications



(\*): impact on phase noise    (\*\*): optional step attenuator option



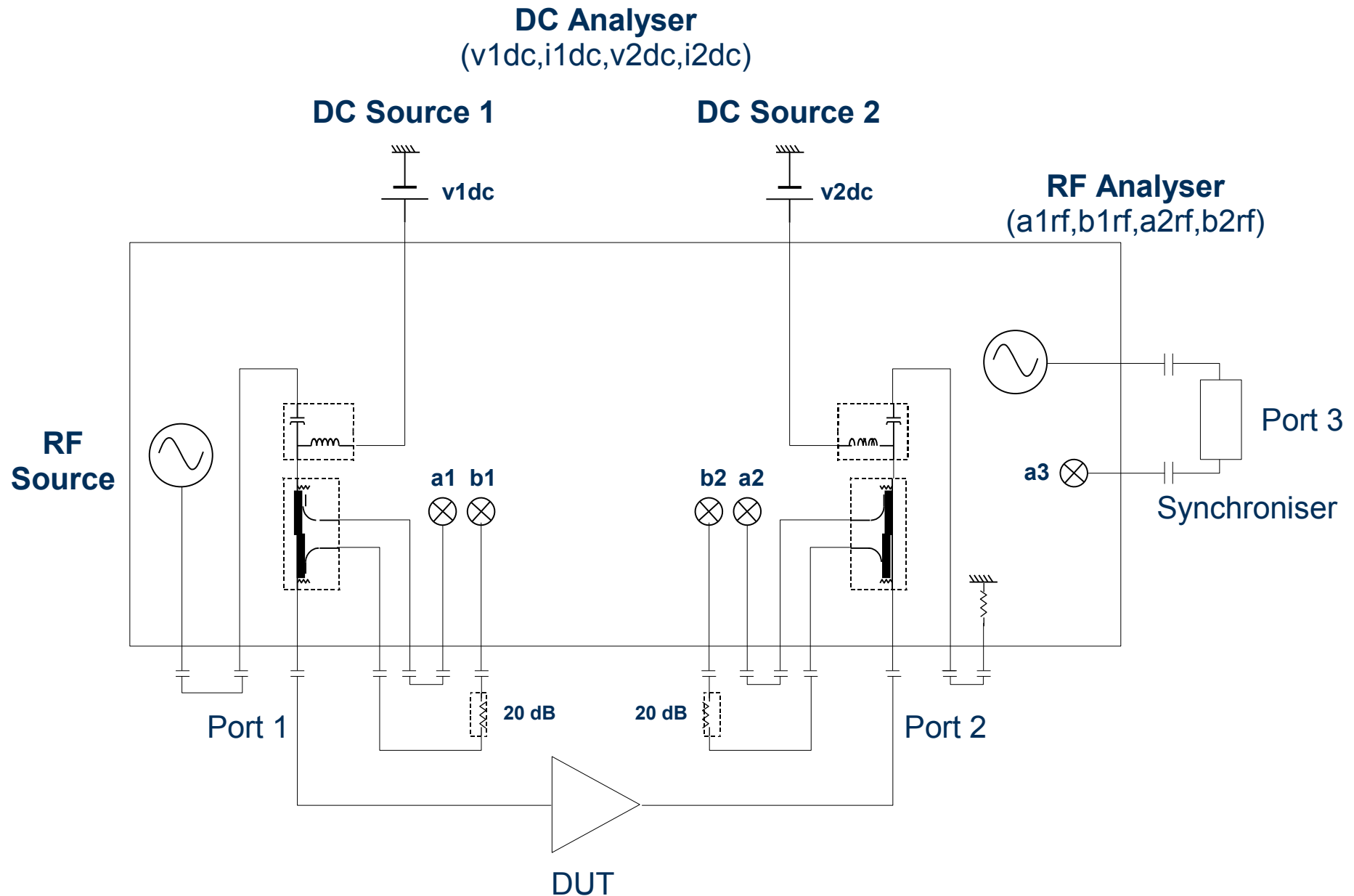
# From Small-Signal To Large-Signal with *one connection*



(\*) EPA120B-100P (Excelics)

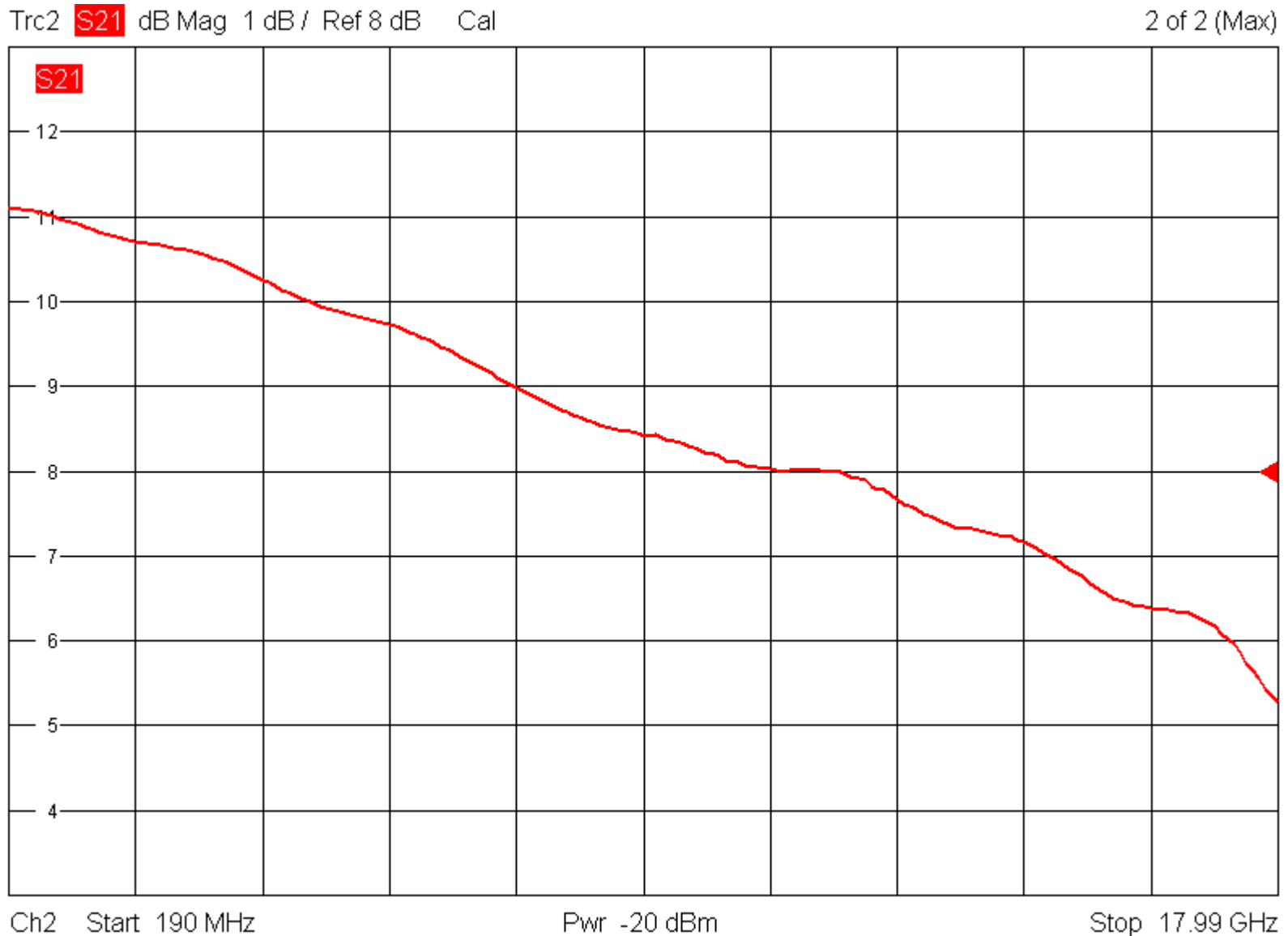
- high efficiency heterojunction power FET
- power output: + 29.0dBm typ.
- power gain: 11.5dB typ. @ 12 GHz

# Classical Measurement Setup



# ZVx(\*): S-parameters

$$v_{gs} = -0.5 \text{ Volt } v_{ds} = 2.0 \text{ Volt } P_{in} = -20 \text{ dBm}$$



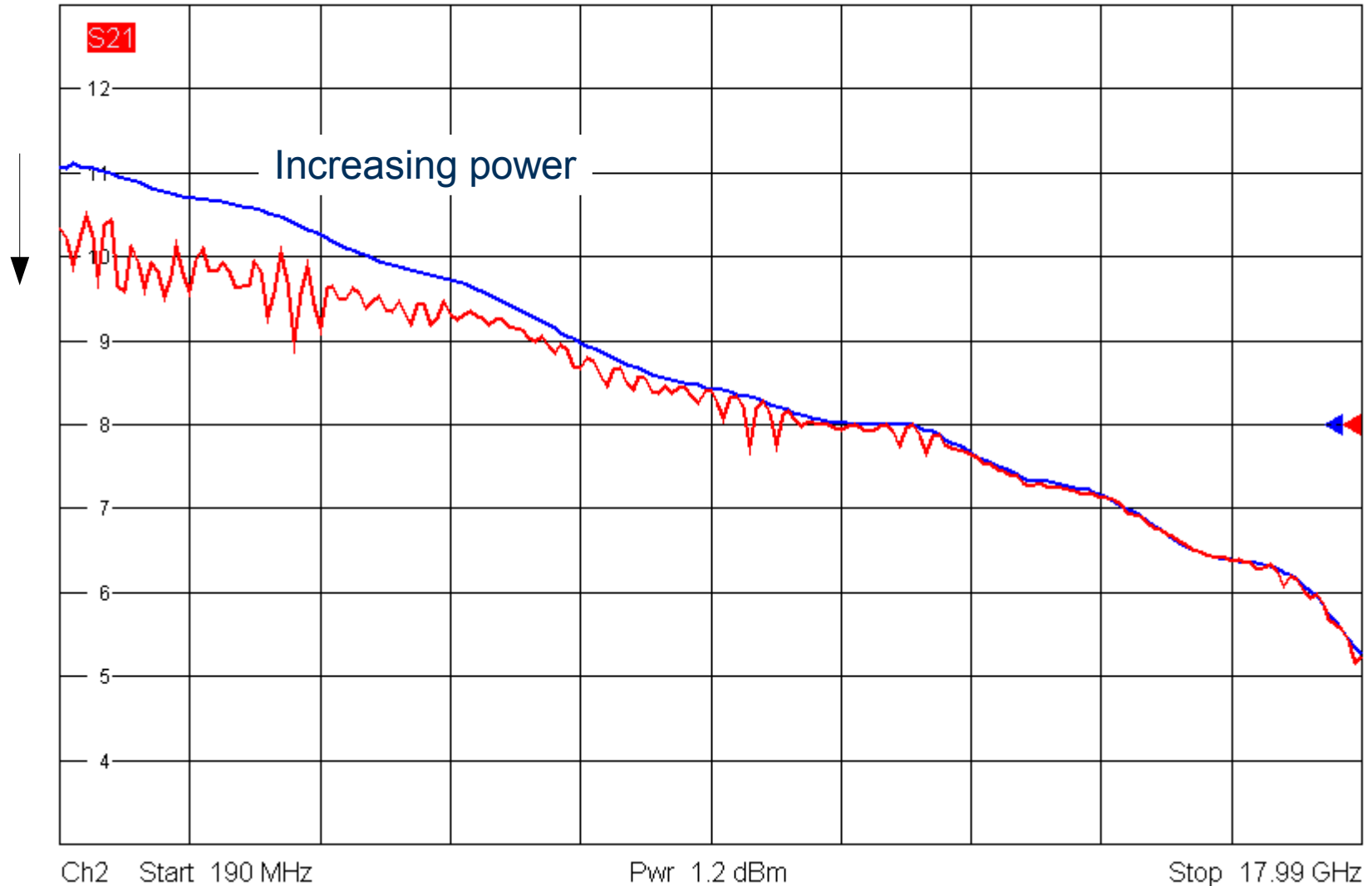
(\*) ZVA or ZVT

# “Noisy” S-parameters ???

$v_{gs} = -0.5 \text{ Volt}$   $v_{ds} = 2.0 \text{ Volt}$   $P_{in} = 0 \text{ dBm}$

Trc2 **S21** dB Mag 1 dB / Ref 8 dB Cal  
Mem3[Trc2] **S21** dB Mag 1 dB / Ref 8 dB

2 of 2 (Max)



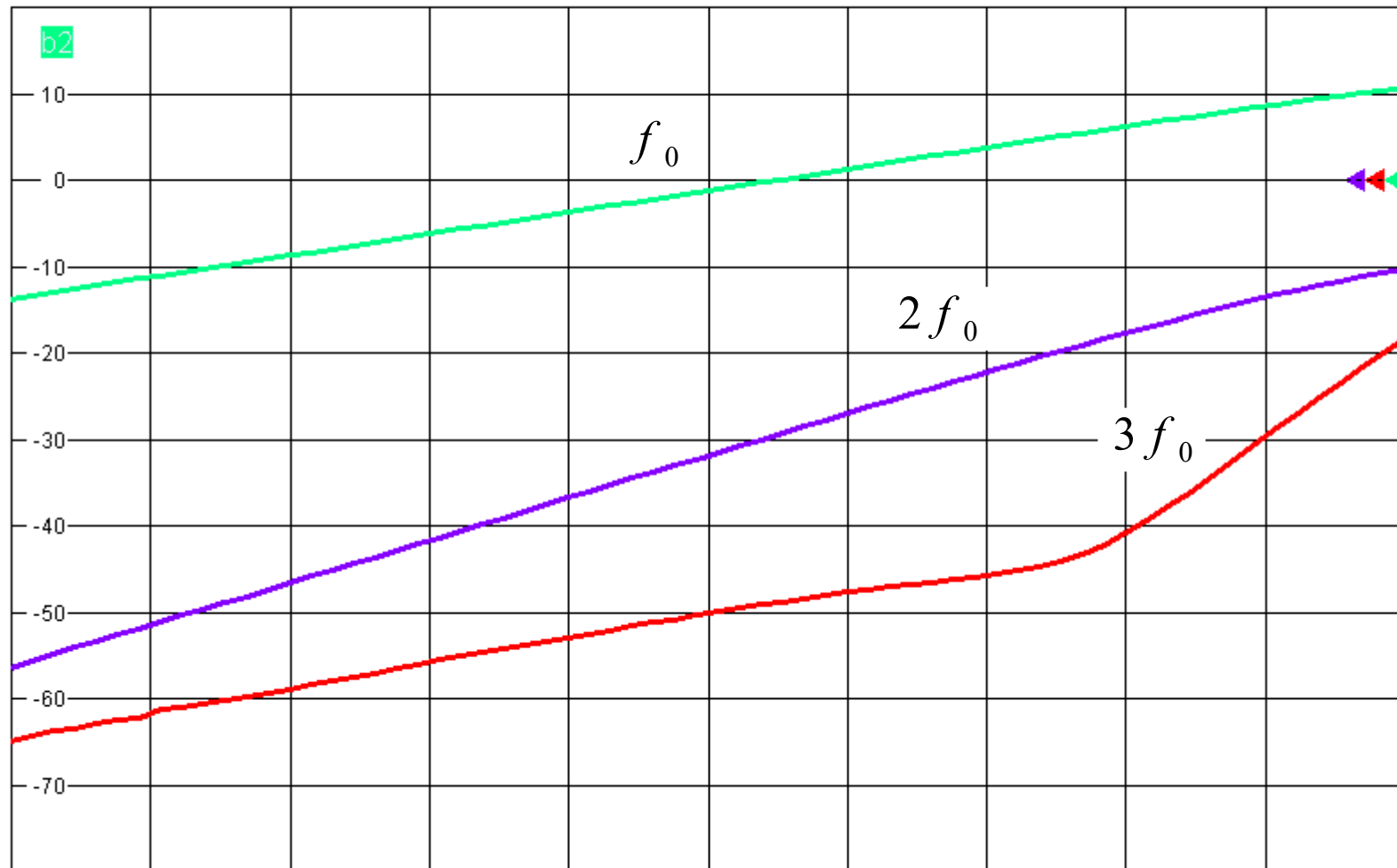
# ZVx: Harmonic Characterisation in Power

$v_{gs} = -0.5$  Volt  $v_{ds} = 2.0$  Volt  $P_{in}$ : from  $-25$  to  $0$  dBm at  $f_0 = 2.059$  GHz

$b_2$

Trc2 b2 dB Mag 10 dB / Ref 0 dBm PCal  
 Mem3[Trc2] b2 dB Mag 10 dB / Ref 0 dBm  
 Mem4[Trc2] b2 dB Mag 10 dB / Ref 0 dBm

2 of 2 (Max)

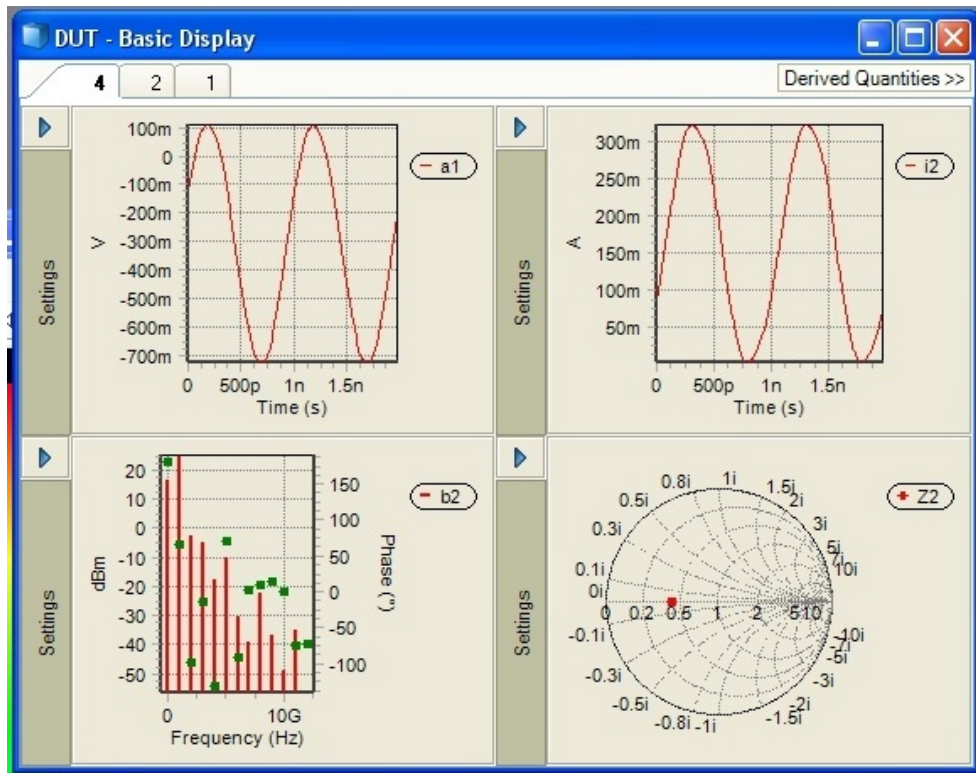


Ch2 H3 Start -25 dBm

Freq 2.059 GHz

Stop 0 dBm

# ZVxPlus: Displays



Basic Display

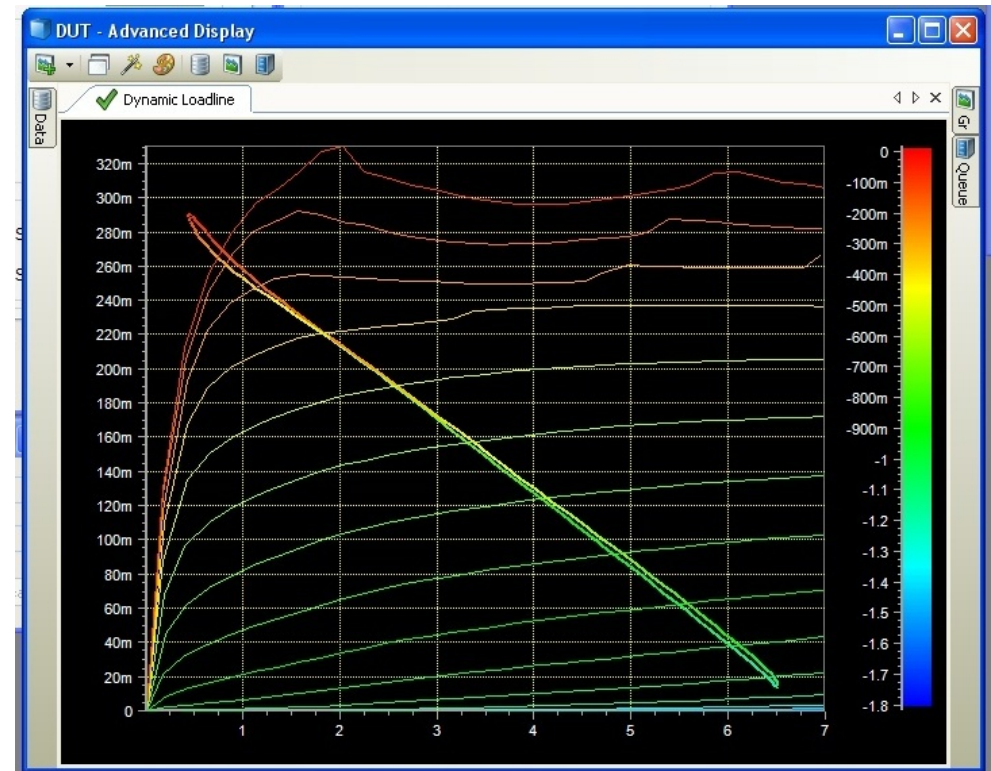
DUT - Derived Quantities

Settings - 1GHz

Quantity	Value	Unit
Gain(f)	22.80541	dB
PAE	42.98027	%
Efficiency	43.07371	%
Pdel_in(f)	-3.06488	dBm
Pdel_out(f)	23.53832	dBm

Derived Quantities

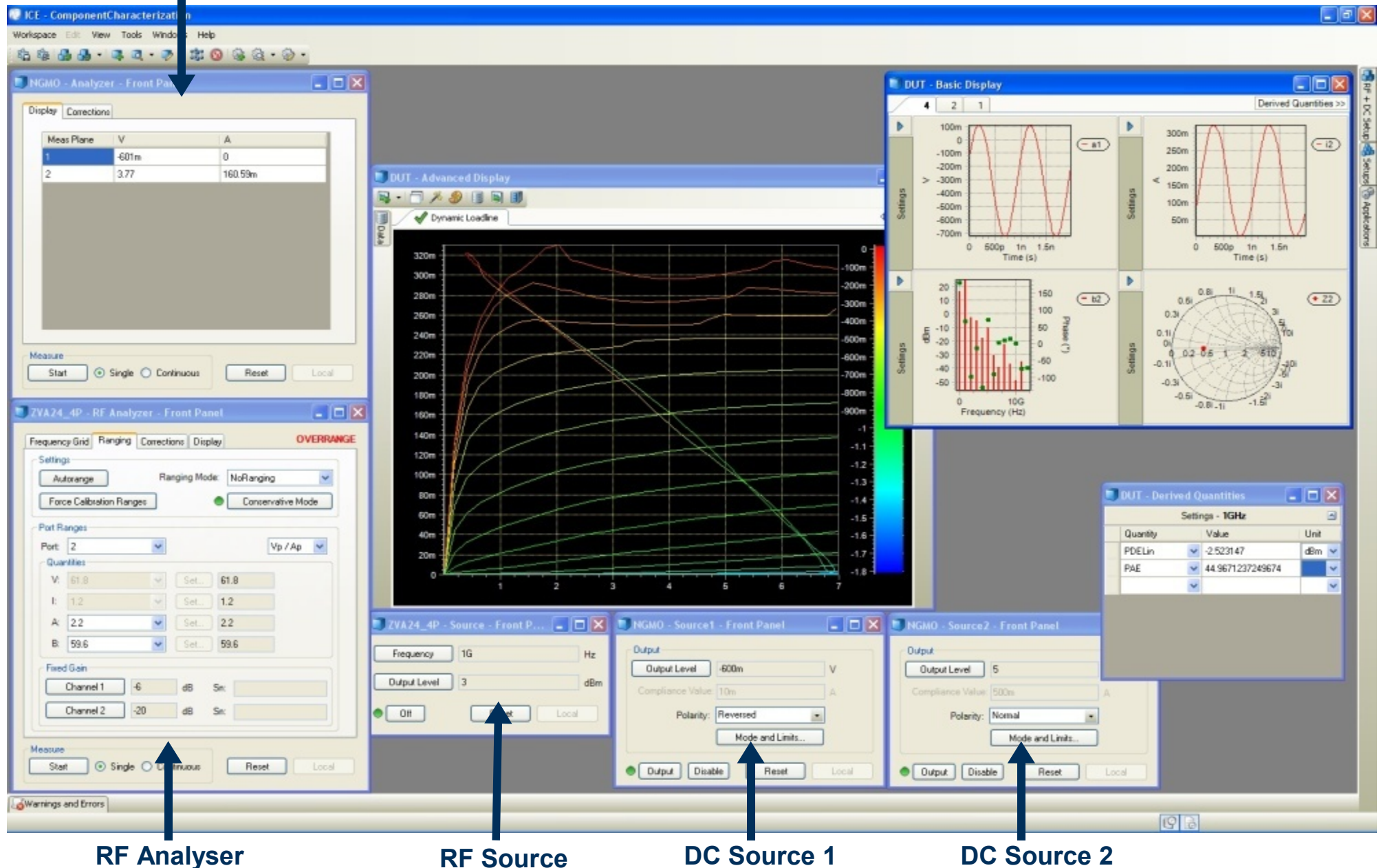
## Advanced Display





# ZVxPlus: Flexible Component Characterisation Software

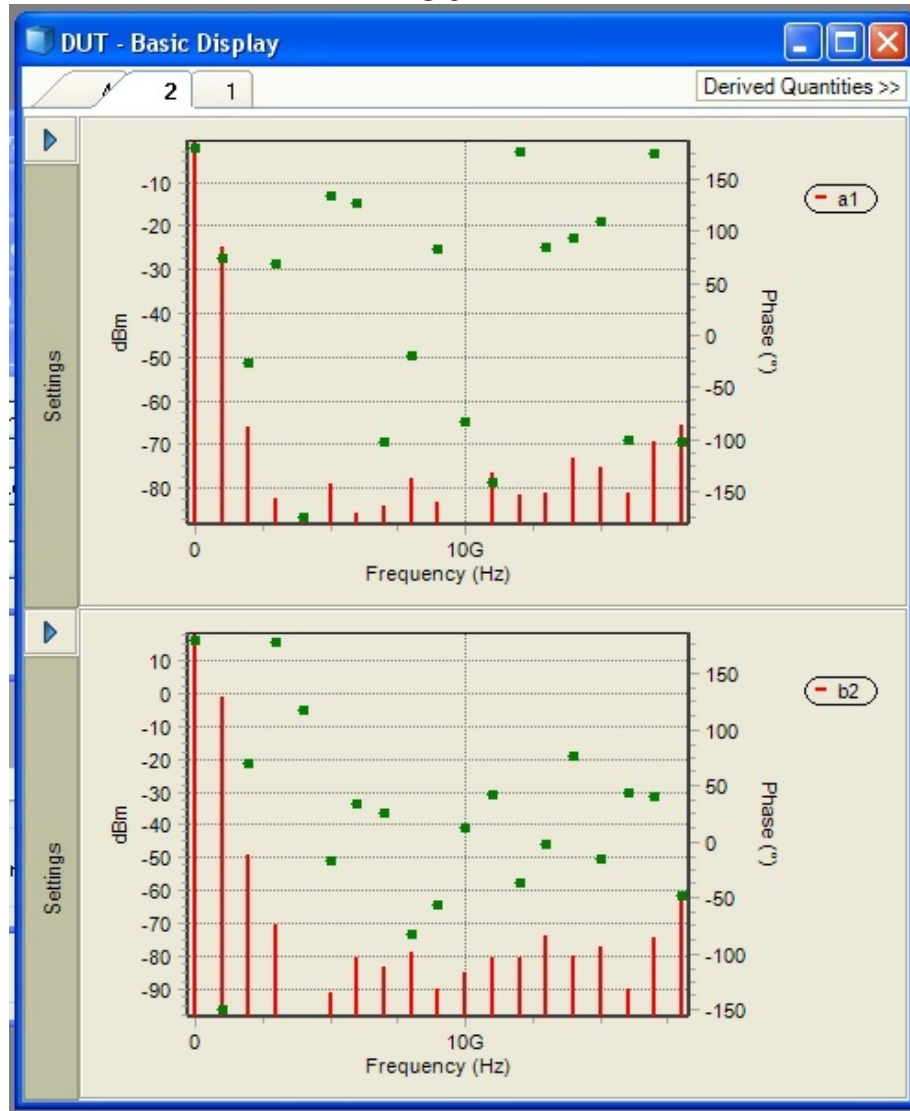
## DC Analyser



# ZVxPlus: Frequency Domain Characterisation - Phase

$$V_{gs} = -0.6V, V_{ds} = 5V, f_0 = 1GHz$$

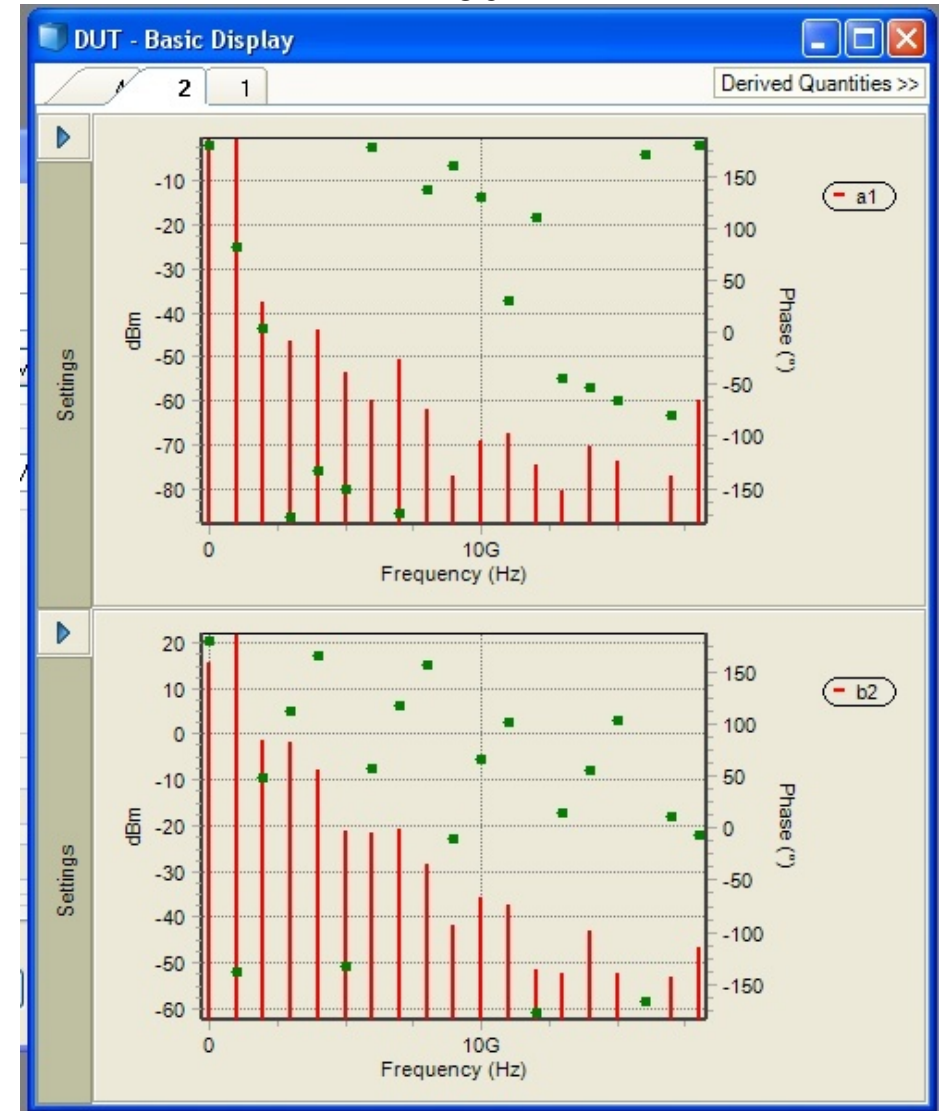
Pin=-25dBm



amplitude

phase

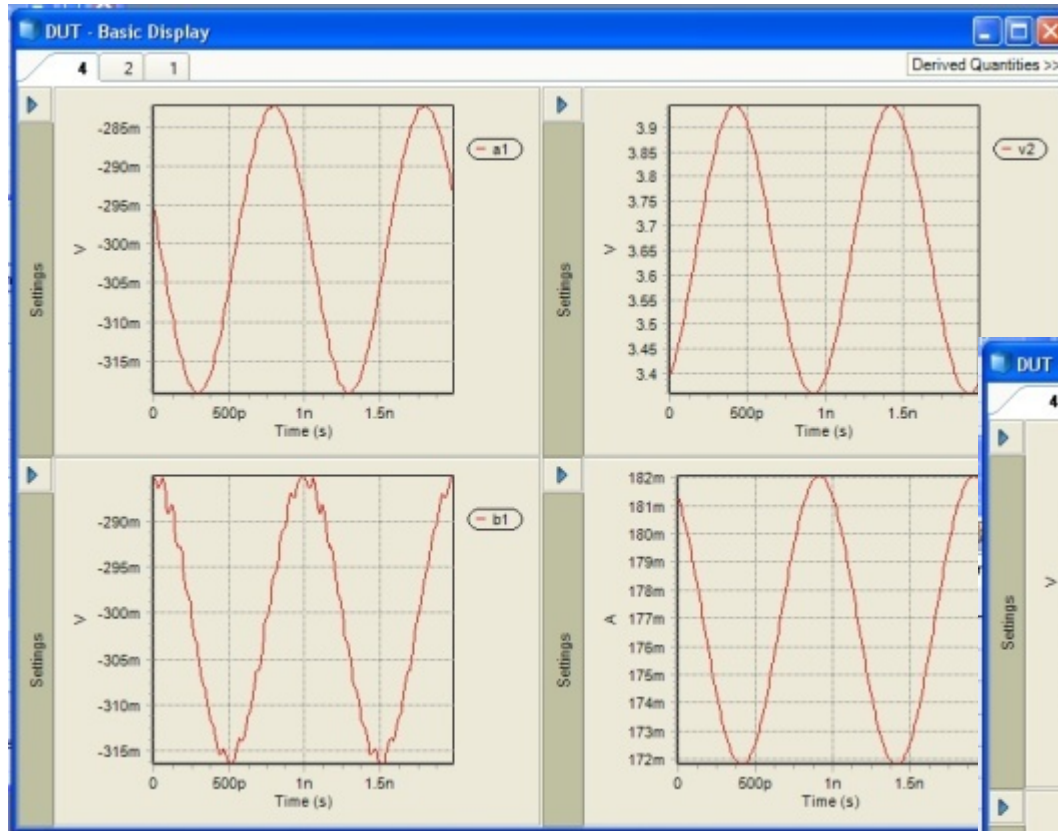
Pin=0dBm



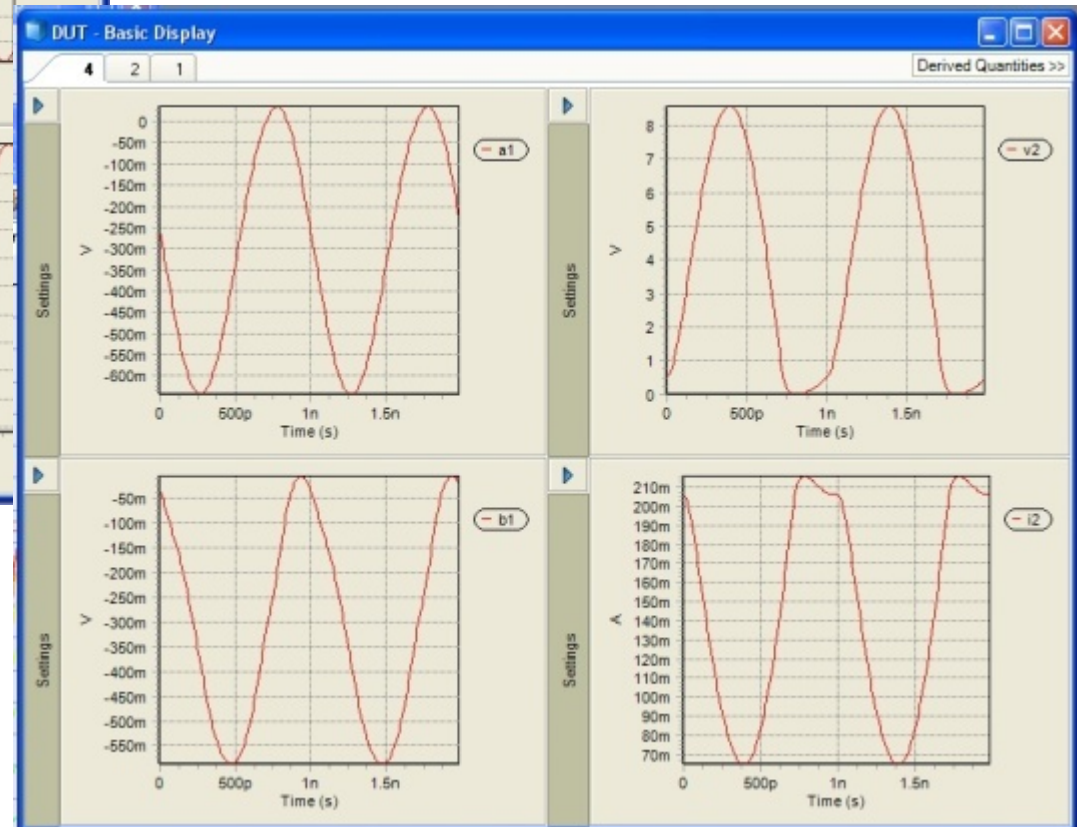


# ZVxPlus: Time Domain Characterisation

$$V_{gs} = -0.6V, V_{ds} = 5V, f_0 = 1GHz$$

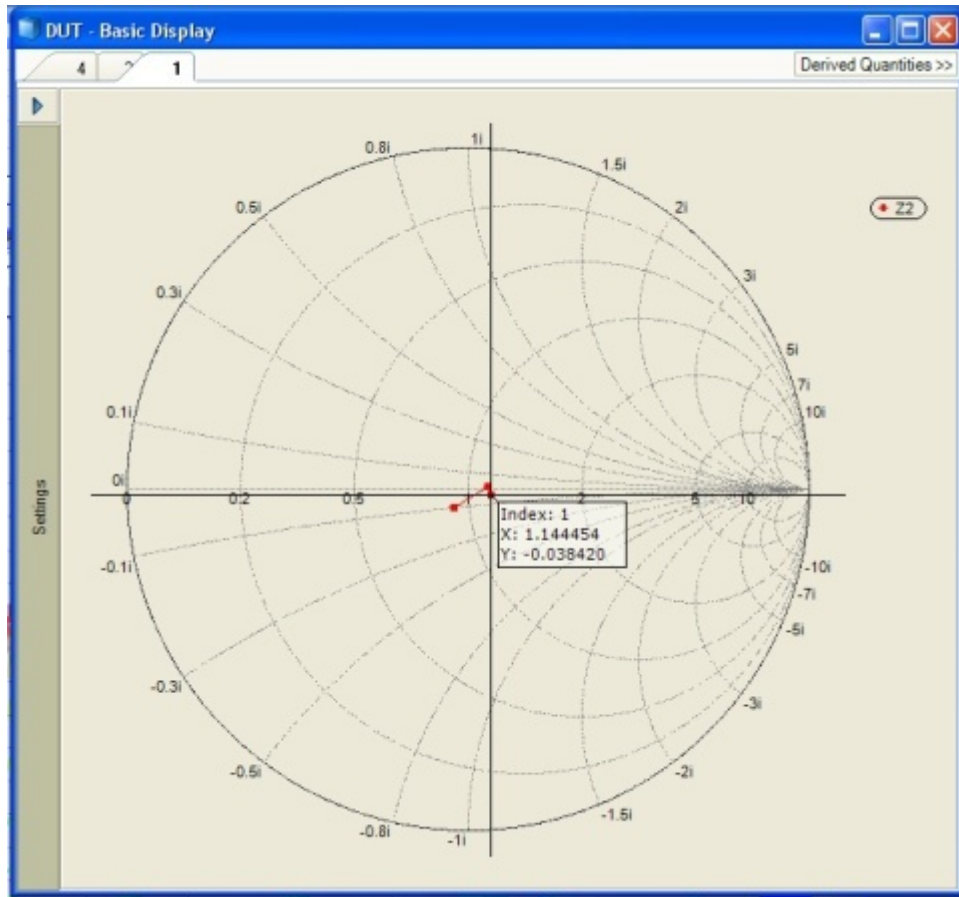


$P_{in} = 0dBm$



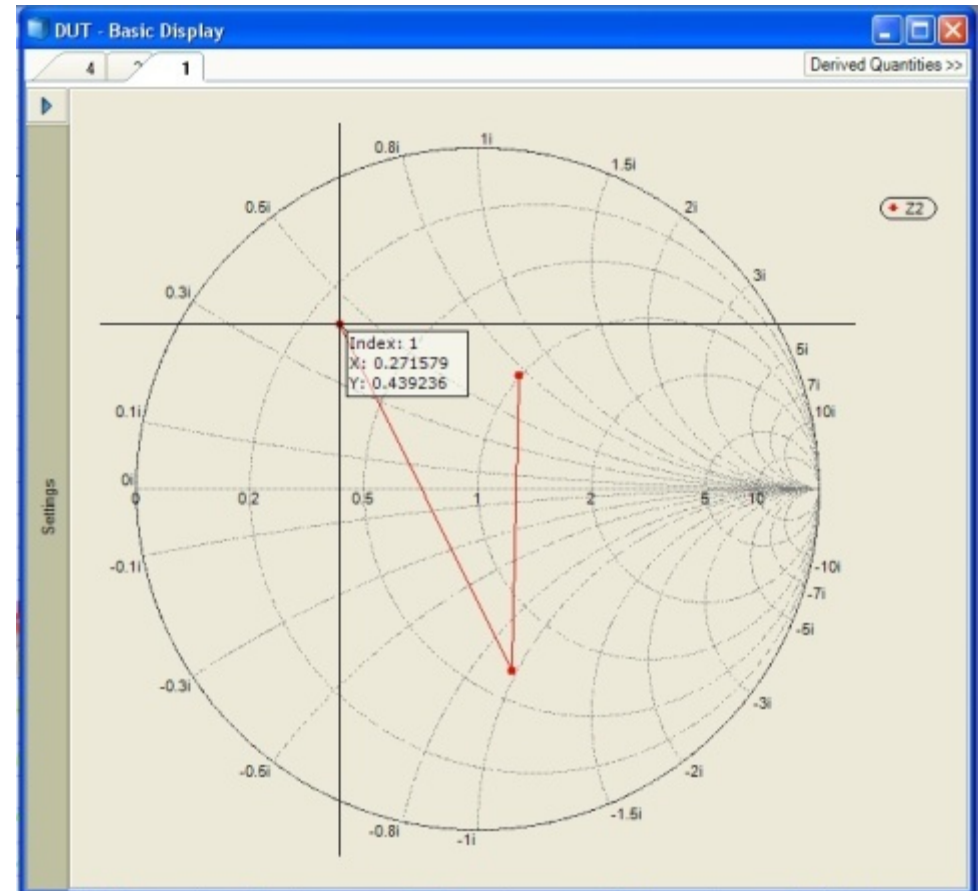
$P_{in} = -25dBm$

# ZVxPlus: Terminating Impedances



Output Impedance with 50 Ohm termination at fundamental and 2 harmonics

Output Impedance with Open termination at fundamental and 2 harmonics



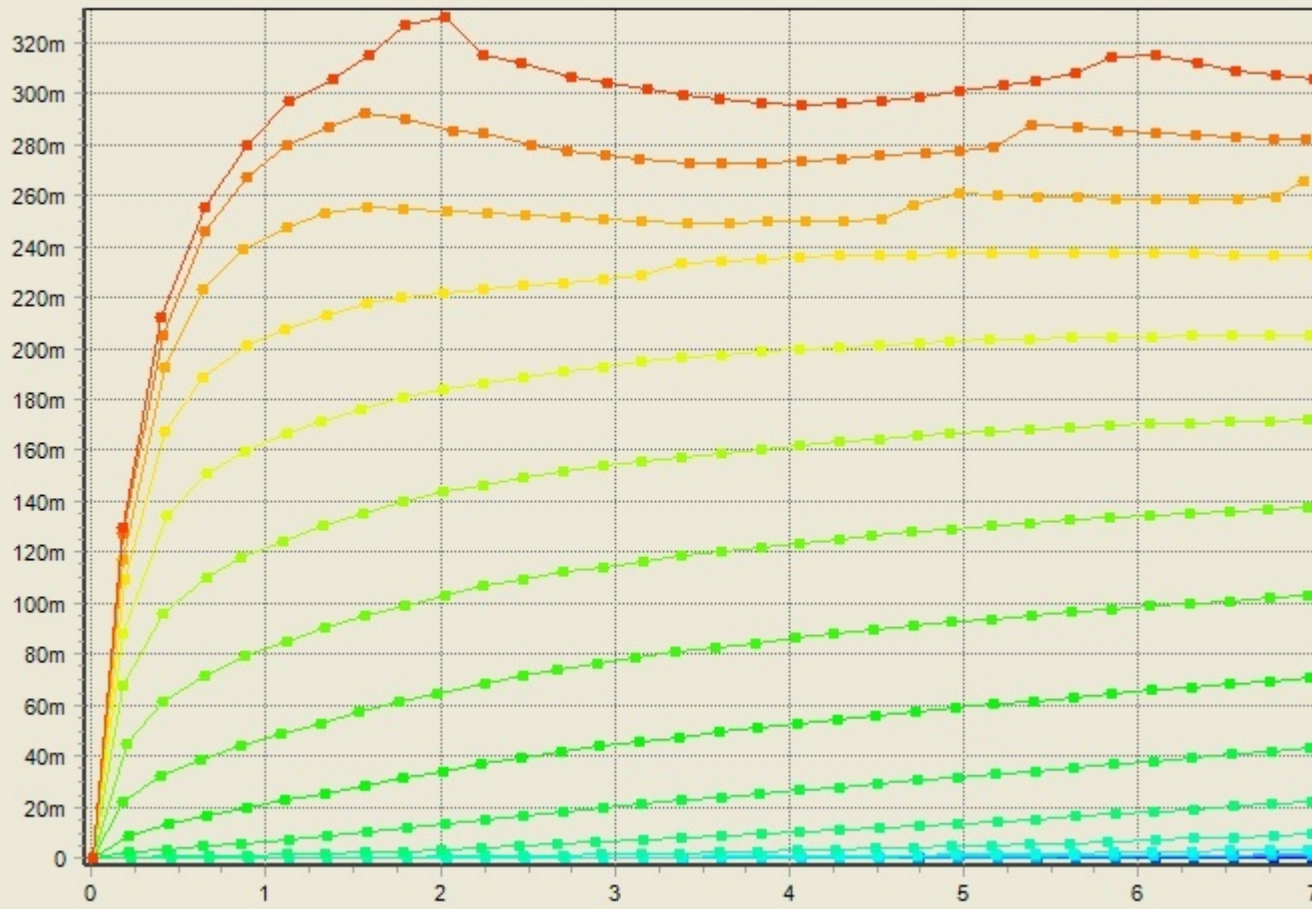
# ZVxPlus: DC IV Application

## DC Sweep Parameters

Sweeps:

	Min	Max	# Steps	Control Loop?	Max Diff	Max # Loops
Vgate	-1.8	-100m	18	<input checked="" type="checkbox"/>	10m	10
Vdrain	0	7	29	<input checked="" type="checkbox"/>	10m	20

Capability to force the control variables in the calibration plane



Defining limits at DC source and in calibration plane

### DC Sweep Limits

Port: Vdrain

Source ☒ Drain ☒

Mode: Voltage

Visualize...

Voltage (V)	Current (A)
0	500m
15	500m

Point

Voltage (V) 0

Current (A) 500m

Interpolation Order: 0

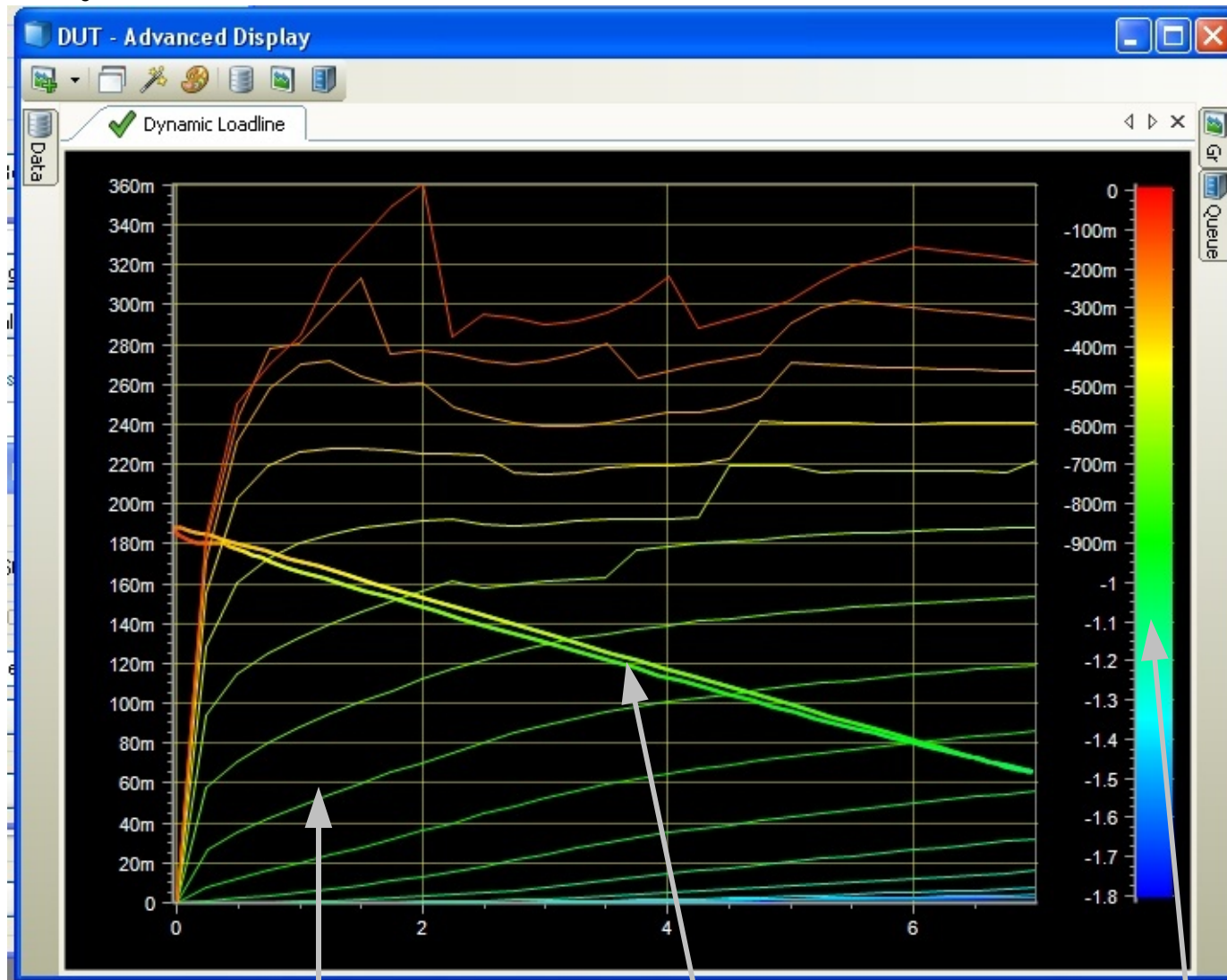
Max Power (W): 5

OK Cancel



# ZVxPlus: 3D Dynamic Loadline

$V_{gs} = -0.6V$ ,  $V_{ds} = 4V$   $f_0 = 1GHz$   $P_{in} = 0 \text{ dBm}$



Compare the static  $V_{gate}$  with the dynamic  $V_{gate}$  through color Z-axis

# Conclusion

- With an incremental investment on a suitable R&S ZVA or ZVT, it is possible to characterise devices with one single connection
  - small-signal behaviour: S-parameters
  - large-signal harmonic behaviour under realistic conditions: complete input and output waveforms
- The accurate and complete large-signal harmonic measurements enable new insights in component behaviour, resulting in
  - better semiconductor technologies
  - better models and design kits
  - better designs
  - faster ways of testing, possibly in non-50 Ohm environments

**For more information**

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[www.nmdg.be](http://www.nmdg.be)